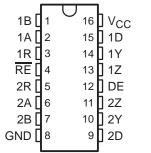
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- Meet or Exceed the Requirements of ANSI Standards TIA/EIA-422-B and TIA/EIA-485-A and ITU Recommendations V.10 and V.11
- **Designed for Multipoint Bus Transmission** on Long Bus Lines in Noise Environments
- **Driver Positive- and Negative-Current** Limiting
- **Thermal Shutdown Protection**
- **Driver 3-State Outputs**
- **Receiver Common-Mode Input Voltage** Range of -12 V to 12 V
- Receiver Input Sensitivity . . . ±200 mV
- Receiver Hysteresis . . . 50 mV Typ
- Receiver Input Impedance . . . 12 k Ω Min
- Receiver 3-State Outputs (SN751177 Only)
- **Operate From Single 5-V Supply**

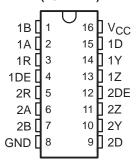
description

The SN751177 and SN751178 dual differential drivers and receivers are monolithic integrated circuits that are designed for balanced multipoint bus transmission at rates up to 10 Mbit/s. They are designed to improve the performance of full-duplex data communications over long bus lines and meet ANSI Standards TIA/EIA-422-B and TIA/EIA-485-A and ITU Recommendations V.10 and V.11.

SN751177 . . . N OR NS[†] PACKAGE (TOP VIEW)



SN751178...N OR NS[†] PACKAGE (TOP VIEW)



† The NS package is only available taped and reeled.

The SN751177 and SN751178 driver outputs provide limiting for both positive and negative currents and thermal-shutdown protection from line-fault conditions on the transmission bus line.

The receiver features high input impedance of at least 12 k Ω , an input sensitivity of ± 200 mV over a common-mode input voltage range of -12 V to 12 V, and typical input hysteresis of 50 mV. Fail-safe design ensures that if the receiver inputs are open, the receiver outputs always will be high.

The SN751177 and SN751178 are characterized for operation from -20°C to 85°C.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.



Function Tables

SN751177, SN751178 (each driver)

INPUT	ENABLE	OUTI	PUTS
D	DE	Υ	Z
Н	Н	Н	L
L	Н	L	Н
Х	L	Z	Z

H = high level, L = low level, X = irrelevant, Z = high impedance (off)

SN751177 (each receiver)

DIFFERENTIAL INPUTS A – B	ENABLE RE	OUTPUT R
V _{ID} ≥ 0.2 V	L	Н
–0.2 V < V _{ID} < 0.2 V	L	?
V _{ID} ≤ -0.2 V	L	L
X	Н	Z
Open	L	Н

H = high level, L = low level, ? = indeterminate, X = irrelevant, Z = high impedance (off)

SN751178 (each receiver)

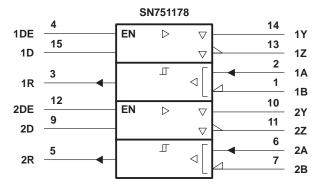
DIFFERENTIAL INPUTS A – B	OUTPUT R
V _{ID} ≥ 0.2 V	Н
$-0.2 \text{ V} < \text{V}_{\text{ID}} < 0.2 \text{ V}$?
V _{ID} ≤ -0.2 V	L

H = high level, L = low level, ? = indeterminate



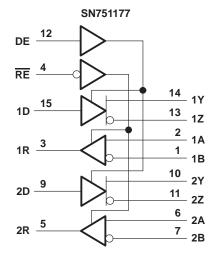
logic symbols†

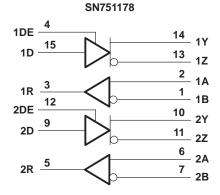
SN751177 12 EN1 DE 4 RE EN2 14 \triangleright 1 ▽ 1Y 15 1D 13 1 ▽ 1Z 2 I 1A 1R ▽ 2 \triangleleft 1 1B 10 \triangleright 1 ▽ 9 2Y 2D 11 1 ▽ **2Z** 6 ┚ 5 **2**A 2R ◁ ▽ 2 7 2B



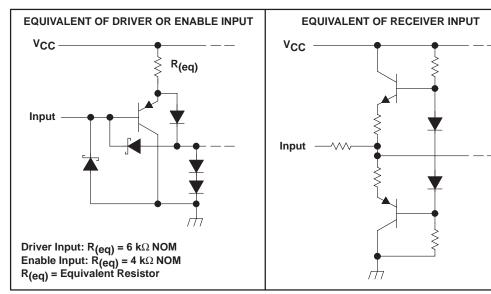
[†] These symbols are in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagrams (positive logic)





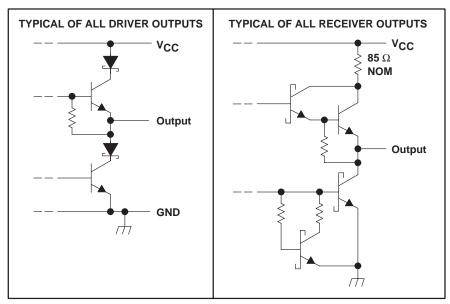
schematics of inputs



All resistor values are nominal.



schematics of outputs



All resistor values are nominal.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage, V _{CC} (see Note 1)	7 V
Input voltage, V _I (DE, RE, and D inputs)	
Receiver input voltage range, V _I (A or B inputs)	
Receiver differential input voltage range, V _{ID} (see Note 2)	
Driver output voltage range, V _O	
Receiver low-level output current, I _{OL}	50 mA
Package thermal impedance, θ_{JA} (see Note 3): N package	
NS package	
Storage temperature range, T _{Stq}	
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	260°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. All voltage values, except differential input voltage, are with respect to the network ground terminal.
 - 2. Differential input voltage is measured at the noninverting terminal with respect to the inverting terminal.
 - 3. The package thermal impedance is calculated in accordance with JESD 51, except for through-hole packages, which use a trace length of zero.



SN751177, SN751178 DUAL DIFFERENTIAL DRIVERS AND RECEIVERS

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recommended operating conditions

				MAX	UNIT
Supply voltage, V _{CC}		4.75	5	5.25	V
High-level input voltage, VIH	DE DE 10: /	2			V
Low-level input voltage, V _{IL}	DE, RE, and D inputs			0.8	V
Common-mode output voltage, VOC		_7 [†]		12	V
High-level output current, IOH	Driver			-60	mA
Low-level output current, IOL				60	mA
Common-mode input voltage, V _{IC}				±12	V
Differential input voltage, V _{ID}	Receiver			±12	V
High-level output current, IOH	Receiver			-400	μΑ
Low-level output current, IOL				16	mA
Operating free-air temperature, T _A		-20		85	°C

[†] The algebraic convention, where the less positive (more negative) limit is designated as minimum, is used in this data sheet for common-mode output and threshold voltage levels only.

DRIVER SECTIONS

electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

	PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
VIK	Input clamp voltage	I _I = -18 mA					-1.5	V
Vон	High-level output voltage	V _{IH} = 2 V,	V _{IL} = 0.8 V,	$I_{OH} = -33 \text{ mA}$		3.7		V
VOL	Low-level output voltage	V _{IH} = 2 V,	V _{IL} = 0.8 V,	$I_{OH} = 33 \text{ mA}$		1.1		V
VOD1	Differential output voltage	IO = 0			1.5		6	V
V _{OD2}	Differential output voltage	$R_L = 100 \Omega$,	See Figure 1		2 or 1/2 V _{O[}	D1 [‡]		٧
		$R_L = 54 \Omega$,	See Figure 1		1.5		5	
V _{OD3}	Differential output voltage	See Note 4			1.5		5	V
Δ VOD	Change in magnitude of differential output voltage (see Note 5)						±0.2	V
Voc	Common-mode output voltage	R_L = 54 Ω or 100 Ω , See Figure 1			-1§		3	V
Δ VOC	Change in magnitude of common-mode output voltage (see Note 5)						±0.2	V
IO	Output current with power off	$V_{CC} = 0$,	$V_O = -7 \text{ V to}$	12 V			±100	μΑ
loz	High-impedance-state output current	$V_0 = -7 \text{ V to } 1$	12 V				±100	μΑ
lН	High-level input current	V _{IH} = 2.7 V					20	μΑ
IIL	Low-level input current	V _{IL} = 0.4 V					-100	μΑ
		$V_0 = -7 \text{ V}$					-250	
los	Short-circuit output current (see Note 6)	VO = VCC				250	mA	
		V _O = 12 V					250	
Icc	Supply current	No load	Outputs enabl	ed		80	110	mA
100	оцрру синен	140 load	Outputs disab	led		50	80	ША

NOTES: 4. See TIA/EIA-485-A Figure 3.5, Test Termination Measurement 2

- 5. Δ|VOD| and Δ|VOC| are the changes in magnitude of VOD and VOC, respectively, that occur when the input is changed from a high level to a low level.
- 6. Not more than one output should be shorted at a time, and the duration of the short circuit should not exceed one second.

switching characteristics at V_{CC} = 5 V, C_L = 50 pF, T_A = 25°C

	PARAMETER		TEST CONDITIONS		TYP	MAX	UNIT
td(OD)	Differential output delay time	$R_L = 54 \Omega$,	See Figure 3		20	25	ns
t _t (OD)	Differential output transition time		11 - 54 52,	See Figure 5		27	35
^t PLH	Propagation delay time, low- to high-level output	$R_1 = 27 \Omega$	See Figure 4		20	25	ns
tPHL	Propagation delay time, high- to low-level output	K = 27.52,	See Figure 4		20	25	ns
^t PZH	Output enable time to high level	$R_L = 110 \Omega$,	See Figure 5		80	120	ns
tPZL	Output enable time to low level	$R_L = 110 \Omega$,	See Figure 6		40	60	ns
^t PHZ	Output disable time from high level	$R_L = 110 \Omega$,	See Figure 5		90	120	ns
tPLZ	Output disable time from low level	$R_L = 110 \Omega$,	See Figure 6		30	45	ns



[†] All typical values are at V_{CC} = 5 V and T_A = 25°C. ‡ The minimum V_{OD2} with a 100- Ω load is either 1/2 V_{OD1} or 2 V, whichever is greater.

[§] The algebraic convention, where the less positive (more negative) limit is designated as minimum, is used in this data sheet for common-mode output and threshold voltage levels only.

SYMBOL EQUIVALENTS

DATA-SHEET PARAMETER	TIA/EIA-422-B	TIA/EIA-485-A
Vod1	Vo	VO
V _{OD2}	$V_t (R_L = 100 \Omega)$	$V_t (R_L = 54 \Omega)$
IVOD3l		V _t (Test Termination Measurement 2)
Δ V _{OD}	$ V_t - \overline{V}_t $	$ V_t - \overline{V}_t $
Voc	V _{OS}	V _{OS}
∆ Voc	Vos - Vos	Vos - Vos
los	I _{sa} , I _{sb}	
lo	$ I_{xa} , I_{xb} $	l _{ia} , l _{ib}

RECEIVER SECTIONS

electrical characteristics over recommended ranges of common-mode input voltage, supply voltage, and operating free-air temperature (unless otherwise noted)

	PARAMETER		TEST CO	NDITIONS	MIN	TYP [†]	MAX	UNIT	
V _{IT+}	Positive-going input threshold voltage		$V_0 = 2.7 V$,	$I_{O} = -0.4 \text{ mA}$			0.2	V	
V _{IT} _	Negative-going input threshold voltage		$V_0 = 0.5 V$,	I _O = 16 mA	-0.2‡			V	
V _{hys}	Input hysteresis voltage (V _{IT+} - V _{IT-})					50		mV	
VIK	Enable clamp voltage	SN751177	I _I = -18 mA				-1.5	V	
Vон	High-level output voltage		V _{ID} = 200 mV,	I _{OH} = -400 μA	2.7			V	
\/	Low level output voltage		V 000 V	\/ 000 m\/	IOL = 8 mA			0.45	V
VOL	Low-level output voltage		V _{ID} = -200 mV	I _{OL} = 16 mA			0.5	V	
loz	High-impedance-state output current	SN751177	$V_0 = 0.4 \text{ V to } 2.4 \text{ V}$				±20	μΑ	
l	Line input current (see Note 7)		Other input at 0.1/	V _I = 12 V			1	mA	
1	Line input current (see Note 7)		Other input at 0 V	V _I = −7 V			-0.8	mA	
lіН	High-level enable input current	SN751177	V _{IH} = 2.7 V				20	μΑ	
I∣L	Low-level enable input current	SN751177	V _{IL} = 0.4 V				-100	μА	
los	Short-circuit output current (see Note 6)		·	-15		-85	μΑ	
Icc	Supply current		No load,	Outputs enabled		80	110	mA	
rį	Input resistance			·	12			kΩ	

 $[\]uparrow$ All typical values are at V_{CC} = 5 V and T_A = 25°C.



[‡] The algebraic convention, where the less positive (more negative) limit is designated as minimum, is used in this data sheet for common-mode output and threshold voltage levels only.

NOTES: 6. Not more than one output should be shorted at a time, and the duration of the short circuit should not exceed one second.

^{7.} Refer to ANSI Standards TIA/EIA-422-B, TIA/EIA-423-A, and TIA/EIA-485-A for exact conditions.

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switching characteristics at V_{CC} = 5 V, C_L = 15 pF, T_A = 25°C

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT	
t _{PLH}	Propagation delay time, low- to high-level	output	V _{ID} = -1.5 V to 1.5 V, See Figure 7			20	35	ns
tPHL	Propagation delay time, high- to low-level	output	$V_{ID} = -1.5 \text{ V to } 1.5 \text{ V},$	See Figure 7		22	35	ns
^t PZH	Output enable time to high level					17	25	ns
tPZL	Output enable time to low level	SN751177	See Figure 8			20	27	ns
tPHZ	Output disable time from high level		See Figure 6			25	40	ns
t _{PLZ}	Output disable time from low level				30	40	ns	

PARAMETER MEASUREMENT INFORMATION

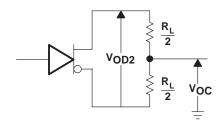


Figure 1. Driver Test Circuit, V_{OD} and V_{OC}

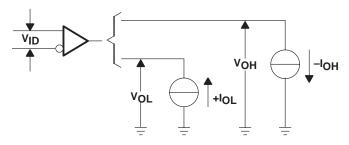
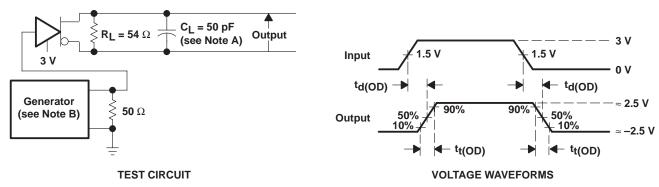


Figure 2. Receiver Test Circuit, VOH and VOL



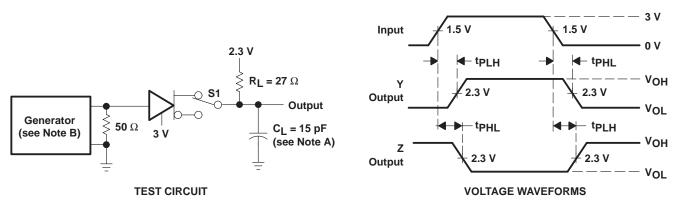
NOTES: A. C_L includes probe and jig capacitance.

B. The pulse generator has the following characteristics: PRR \leq 1 MHz, 50% duty cycle, Z_{Q} = 50 Ω , t_{f} \leq 6 ns, t_{f} \leq 6 ns.

Figure 3. Driver Differential Output-Delay and Transition-Time Test Circuit and Voltage Waveforms



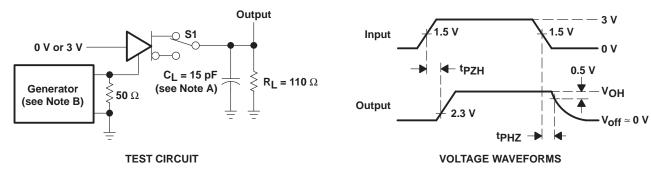
PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_L includes probe and jig capacitance.

B. The pulse generator has the following characteristics: PRR \leq 1 MHz, 50% duty cycle, $Z_O = 50~\Omega$, $t_f \leq 6$ ns. $t_f \leq 6$ ns.

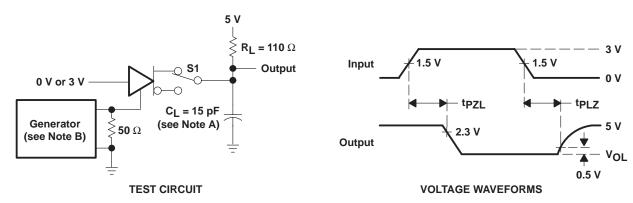
Figure 4. Driver Propagation-Time Test Circuit and Voltage Waveforms



NOTES: A. C_I includes probe and jig capacitance.

B. The pulse generator has the following characteristics: PRR \leq 1 MHz, 50% duty cycle, $Z_O = 50~\Omega$, $t_f \leq$ 6 ns. $t_f \leq$ 6 ns.

Figure 5. Driver Enable- and Disable-Time Test Circuit and Voltage Waveforms



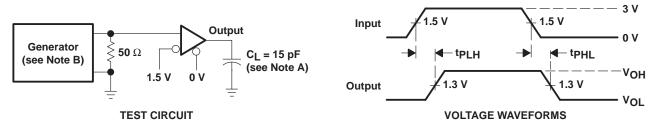
NOTES: A. C_L includes probe and jig capacitance.

B. The pulse generator has the following characteristics: PRR \leq 1 MHz, 50% duty cycle, $Z_O = 50 \Omega$, $t_f \leq 6$ ns, $t_f \leq 6$ ns.

Figure 6. Driver Enable- and Disable-Time Test Circuit and Voltage Waveforms



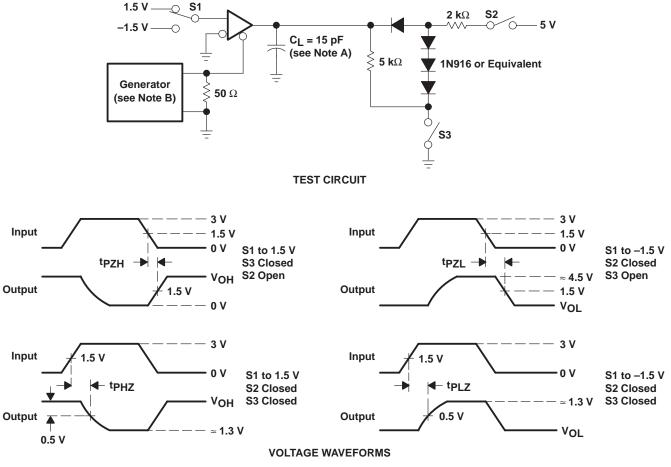
PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_L includes probe and jig capacitance.

B. The pulse generator has the following characteristics: PRR \leq 1 MHz, 50% duty cycle, $Z_O = 50~\Omega$, $t_f \leq 6$ ns. $t_f \leq 6$ ns.

Figure 7. Receiver Propagation-Time Test Circuit and Voltage Waveforms



NOTES: A. C_L includes probe and jig capacitance.

B. The pulse generator has the following characteristics: PRR \leq 1 MHz, 50% duty cycle, $Z_O = 50 \ \Omega$, $t_f \leq 6$ ns, $t_f \leq 6$ ns.

Figure 8. Receiver Output Enable- and Disable-Time Test Circuit and Voltage Waveforms



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